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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

·XFI

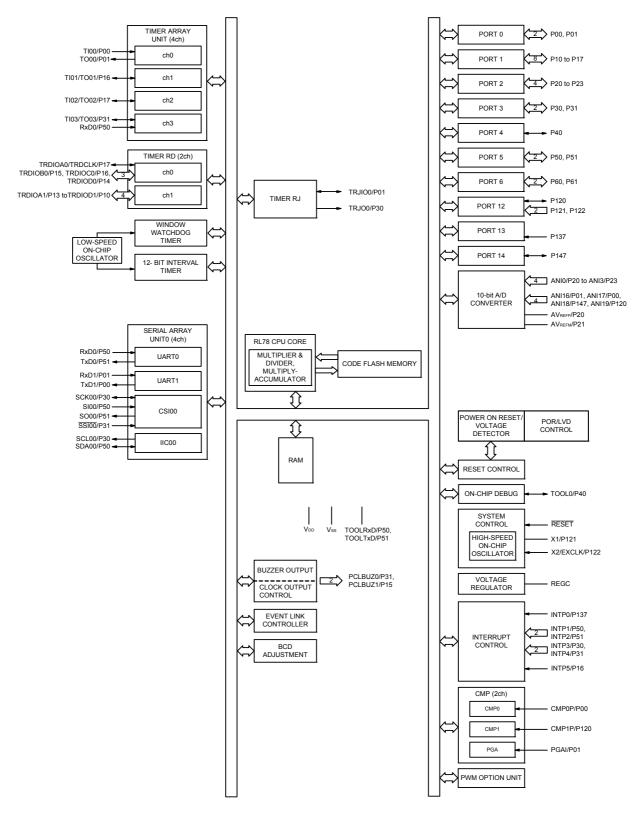
| Product Status | Active |
|----------------------------|---|
| Core Processor | RL78 |
| Core Size | 16-Bit |
| Speed | 24MHz |
| Connectivity | CSI, I ² C, UART/USART |
| Peripherals | LVD, POR, PWM, WDT |
| Number of I/O | 23 |
| Program Memory Size | 16KB (16K x 8) |
| Program Memory Type | FLASH |
| EEPROM Size | - |
| RAM Size | 1.5К х 8 |
| Voltage - Supply (Vcc/Vdd) | 2.7V ~ 5.5V |
| Data Converters | A/D 8x10b |
| Oscillator Type | Internal |
| Operating Temperature | -40°C ~ 85°C (TA) |
| Mounting Type | Surface Mount |
| Package / Case | 30-LSSOP (0.240", 6.10mm Width) |
| Supplier Device Package | 30-LSSOP |
| Purchase URL | https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f11eaaasp-30 |
| | |

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1.5 Block Diagram

1.5.1 30-pin products





1.6 **Outline of Functions**

[30-pin, 32-pin, 44-pin products (code flash memory 8 KB to 16 KB)]

Caution The above outline of the functions applies when peripheral I/O redirection register 1 (PIOR1) is set to 00H.

| | | | | (1/2) | | | | |
|--|--|--|------------------------------------|-----------------------------|--|--|--|--|
| | | 30-pin | 32-pin | 44-pin | | | | |
| | Item | R5F11EA8ASP, R5F11EAAASP | R5F11EB8AFP, R5F11EBAAFP | R5F11EF8AFP, R5F11EFAAFP | | | | |
| Code flash m | emory (KB) | 8 to 16 | | | | | | |
| RAM (KB) | | | 1.5 | | | | | |
| Address space | ce | 1 MB | | | | | | |
| Main system clock | High-speed system clock | X1 (crystal/ceramic) oscillation, e LS (low-speed main) mode: 1 to HS (high-speed main) mode: 1 t | 8 MHz (VDD = 2.7 to 5.5 V), | (EXCLK) | | | | |
| | High-speed on-chip oscillator clock (fiH) | LS (low-speed main) mode: 1 to HS (high-speed main) mode: 1 | , , , | | | | | |
| Low-speed on-chip oscillator clock 15 kHz (TYP.): VDD = 2.7 to 5.5 V | | | | | | | | |
| General-purp | oose register | 8 bits × 32 registers (8 bits × 8 registers × 4 banks) | | | | | | |
| Minimum inst | truction execution | 0.04167 μs (High-speed on-chi | o oscillator clock: fiн = 24 MHz o | peration) | | | | |
| time | | 0.05 μ s (High-speed system clo | ck: fmx = 20 MHz operation) | | | | | |
| Instruction se | 20 | Data transfer (8/16 bits) Adder and subtractor/logical operation (8/16 bits) Multiplication (8 bits × 8 bits, 16 bits × 16 bits), Division (16 bits ÷ 16 bits, 32 bits ÷ 32 bits) Multiplication and Accumulation (16 bits × 16 bits + 32 bits) Rotate, barrel shift, and bit manipulation (Set, reset, test, and Boolean operation), etc. | | | | | | |
| I/O port | Total | 26 | 28 | 40 | | | | |
| | CMOS I/O | 23 | 25 | 35 | | | | |
| | CMOS input | 3 | 3 | 5 | | | | |
| | CMOS output | | | | | | | |
| | N-ch open-drain I/O (6 V tolerance) | | _ | | | | | |
| Timer | 16-bit timer | 7 channels (TAU: 4 channels, Timer RJ: 1 channel, Timer RD: 2 channels) | | | | | | |
| | Watchdog timer | 1 channel | | | | | | |
| | 12-bit interval timer | 1 channel | | | | | | |
| | Timer output | Timer outputs: 14 channels PWM outputs: 9 channels | | | | | | |

Caution Since a library is used when rewriting the flash memory using the user program, flash ROM and RAM areas are used. Refer to the RL78 Family Flash Self-Programming Library Type01 User's Manual before using these products.



2. ELECTRICAL SPECIFICATIONS

Caution 1. The RL78 microcontroller has an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.

Caution 2. The pins mounted are as follows according to product.

2.1 Pins Mounted According to Product

2.1.1 Port functions

Refer to 2.1.1 30-pin products, 2.1.2 32-pin products, and 2.1.3 44-pin products in the RL78/G1G User's Manual.

2.1.2 Non-port functions

Refer to 2.2.1 With functions for each product in the RL78/G1G User's Manual.



Absolute Maximum Ratings

(2/2)

| | aango | | | | (212) |
|----------------------|--------|----------------------|---|-------------|-------|
| Parameter | Symbol | | Conditions | Ratings | Unit |
| Output current, high | Іон1 | Per pin | P00, P01, P10 to P17, P30, P31, P40, P41, P50, P51, P60 to P63, P70 to P73, P120, P146, P147 | -40 | mA |
| | | Total of all | P00, P01, P40, P41, P120 | -70 | mA |
| | | pins -170 mA | P10 to P17, P30, P31, P50, P51, P60 to P63, P70 to P73, P146, P147 | -100 | mA |
| | Іон2 | Per pin | P20 to P27 | -0.5 | mA |
| | | Total of all pins | | -2 | mA |
| Output current, low | IOL1 | Per pin | P00, P01, P10 to P17, P30, P31, P40, P41, P50, P51, P60 to P63, P70 to P73, P120, P146, P147 | 40 | mA |
| | | Total of all | P00, P01, P40, P41, P120 | 70 | mA |
| | | pins 170 mA | P10 to P17, P30, P31, P50, P51, P60 to P63, P70 to P73, P146, P147 | 100 | mA |
| | IOL2 | Per pin | P20 to P27 | 1 | mA |
| | | Total of all pins | | 5 | mA |
| Operating ambient | TA | In normal of | pperation mode | -40 to +85 | °C |
| temperature | | In flash me | mory programming mode | | |
| Storage temperature | Tstg | | | -65 to +150 | °C |

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



2.4 DC Characteristics

2.4.1 Pin characteristics

| (TA = -40 to +85°C, 2.7 | $V \leq VDD \leq 5.5 V$, $Vss = 0 V$) |
|-------------------------|---|
|-------------------------|---|

| Items | Symbol | Conditions | | MIN. | TYP. | MAX. | Unit |
|-----------------------------|--------|--|-------------------------------------|------|------|-----------------|------|
| Output current, high Note 1 | | Per pin for P00, P01, P10 to P17, P30, P31, P40, P41, P50, P51, P60 to P63, P70 to P73, P120, P146, P147 | $2.7~V \leq V\text{DD} \leq 5.5~V$ | | | -10.0 Note 2 | mA |
| | | Total of P00, P01, P40, P41, P120 | $4.0~V \leq V \text{DD} \leq 5.5~V$ | | | -55.0 | mA |
| | | (When duty \leq 70% ^{Note 3}) | $2.7~V \leq V_{DD} < 4.0~V$ | | | -10.0 | mA |
| | | Total of P10 to P17, P30, P31, P50, P51, P60 to P63, P70 to P73, P146, P147 (When duty \leq 70% ^{Note 3}) | $4.0~V \leq V \text{DD} \leq 5.5~V$ | | | -80.0 | mA |
| | | | $2.7~V \leq V_{DD} < 4.0~V$ | | | -19.0 | mA |
| | | Total of all pins (When duty \leq 70% ^{Note 3}) | $2.7~V \leq V\text{DD} \leq 5.5~V$ | | | -135.0 | mA |
| | Іон2 | Per pin for P20 to P27 | $2.7~V \leq V\text{DD} \leq 5.5~V$ | | | -0.1 Note 2 | mA |
| | | Total of all pins (When duty \leq 70% ^{Note 3}) | $2.7~V \leq V\text{DD} \leq 5.5~V$ | | | -1.5 | mA |

Note 1. Value of current at which the device operation is guaranteed even if the current flows from the VDD pin to an output pin.

Note 2. Do not exceed the total current value.

Note 3. Specification under conditions where the duty factor ≤ 70%. The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

• Total output current of pins = (IOH × 0.7)/(n × 0.01)

<Example> Where n = 80% and IoH = -10.0 mA

Total output current of pins = (-10.0 × 0.7)/(80 × 0.01) \approx -8.7 mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Caution P00, P10, P15, P17, P30, P50, P51 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



(3) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output) (TA = -40 to +85°C, 2.7 V \leq VDD \leq 5.5 V, Vss = 0 V)

| Parameter | Symbol | Conditions | | HS (high-speed main) mode | | LS (low-speed main) mode | | Unit |
|--|------------|---|--|------------------------------|------|-----------------------------|------|------|
| | | | | MIN. | MAX. | MIN. | MAX. | |
| SCKp cycle time | tксү1 | $t_{KCY1} \geq 4/f_{CLK}$ | $2.7~\text{V} \leq \text{V}_{\text{DD}} \leq 5.5~\text{V}$ | 167 | | 500 | | ns |
| SCKp high-/low-level width | tĸнı, tĸ∟ı | $4.0~\text{V} \leq \text{V}\text{dD} \leq 5.5~\text{V}$ | | tксү1/2 - 12 | | tксү1/2 - 50 | | ns |
| | | $2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$ | | tксү1/2 - 18 | | tксү1/2 - 50 | | ns |
| SIp setup time (to SCKp↑) Note 1 | tsıĸı | $4.0~\text{V} \leq \text{V}_\text{DD} \leq 5.5~\text{V}$ | | 44 | | 110 | | ns |
| | | $2.7 \text{ V} \leq \text{Vdd} \leq 5.5 \text{ V}$ | | 44 | | 110 | | ns |
| SIp hold time (from SCKp [↑]) Note 2 | tksi1 | $2.7~V \leq V_{\text{DD}} \leq$ | 5.5 V | 19 | | 19 | | ns |
| Delay time from SCKp↓ to SOp output Note 3 | tkso1 | $\begin{array}{l} \text{2.7 V} \leq \text{V}_{\text{DD}} \leq \\ \text{C} = 30 \text{ pF} \ ^{\text{Note}} \end{array}$ | | | 25 | | 25 | ns |

Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 4. C is the load capacitance of the SCKp and SOp output lines.

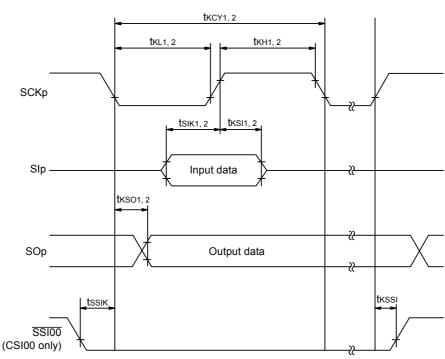
Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark 1. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM number (g = 3, 5)

Remark 2. fMCK: Serial array unit operation clock frequency

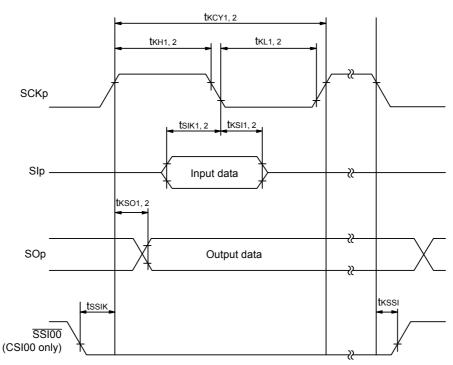
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))





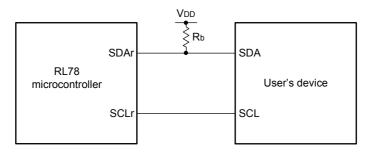
CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)

CSI mode serial transfer timing (during communication at same potential) (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)

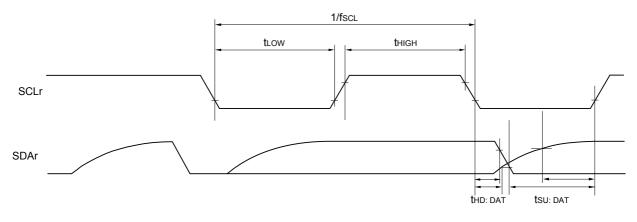


Remark 1. p: CSI number (p = 00) Remark 2. m: Unit number, n: Channel number (mn = 00)

Simplified I²C mode connection diagram (during communication at same potential)



Simplified I²C mode serial transfer timing (during communication at same potential)



- Caution Select the normal input buffer and the N-ch open drain output (VDD tolerance) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register h (POMh).
- Remark 1. Rb[Ω]: Communication line (SDAr) pull-up resistance, Cb[F]: Communication line (SDAr, SCLr) load capacitance
- Remark 2. r: IIC number (r = 00), g: PIM number (g = 3, 5), h: POM number (h = 3, 5)
- Remark 3. fMck: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0), n: Channel number (n = 0), mn = 00)



(6) Communication at different potential (2.5 V, 3 V) (UART mode)

| TA = -40 to - | ⊦85°C, 2. | 7 $V \leq VDD$ | ≤ 5.5 V, Vss = 0 V) | | | | | | |
|---------------|-----------|-----------------------|--|------|----------------------|-------------|--------------------------|------|--|
| Parameter | Symbol | | Conditions | | eed main) mode | LS (low-spe | LS (low-speed main) mode | | |
| | | | | MIN. | MAX. | MIN. MAX. | | | |
| Transfer rate | | Reception | | | fмск/6 Note 1 | | fмск/6 Note 1 | bps | |
| | | | Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 3 | | 4.0 | | 1.3 | Mbps | |
| | | | $\begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V \end{array}$ | | fмск/6 Note 1 | | fмск/6 Note 1 | bps | |
| | | | Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 3 | | 4.0 | | 1.3 | Mbp | |
| | | | $\begin{array}{l} 2.7 \ V \leq V_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_{b} \leq 2.0 \ V \end{array}$ | | fмск/6 Notes 1, 2 | | fмск/6 Notes 1, 2 | bps | |
| | | | Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}$ Note 3 | | 4.0 | | 1.3 | Mbp | |

Transfer rate in the SNOOZE mode is 4800 bps only. Note 1.

However, the SNOOZE mode cannot be used when FRQSEL4 = 1.

Note 2. Use it with $VDD \ge Vb$.

- Note 3. The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are: HS (high-speed main) mode: 24 MHz (2.7 V \leq VDD \leq 5.5 V) LS (low-speed main) mode: 8 MHz (2.7 V \leq VDD \leq 5.5 V)
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- Remark 1. Vb[V]: Communication line voltage
- Remark 2. q: UART number (q = 0, 1), g: PIM and POM number (g = 0, 5)

Remark 3. fMCK: Serial array unit operation clock frequency (Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03)

Remark 4. VIH and VIL below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in UART mode.

 $4.0~\text{V} \leq \text{V}\text{DD} \leq 5.5~\text{V},~2.7~\text{V} \leq \text{V}\text{b} \leq 4.0~\text{V}\text{:}~\text{V}\text{i}\text{H}$ = 2.2 V, ViL = 0.8 V

 $2.7~\text{V} \leq \text{VDD}$ < 4.0 V, 2.3 V $\leq \text{Vb} \leq 2.7$ V: VIH = 2.0 V, VIL = 0.5 V

 $2.7~\text{V} \leq \text{V}\text{DD}$ < $3.3~\text{V},~1.6~\text{V} \leq \text{V}\text{b} \leq 2.0~\text{V}\text{:}$ VIH = 1.50 V, VIL = 0.32 V



(0.0)

(6) Communication at different potential (2.5 V, 3 V) (UART mode)

| Parameter | Symbol | | Conditions | HS (high-spe | eed main) mode | LS (low-spe | ed main) mode | Unit |
|---------------|--------|--------------|--|--------------|----------------|-------------|---------------|------|
| | | | | MIN. | MAX. | MIN. | MAX. | |
| Transfer rate | | transmission | | | Note 1 | | Note 1 | bps |
| | | | Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 1.4 k Ω , V_b = 2.7 V | | 2.8 Note 2 | | 2.8 Note 2 | Mbps |
| | | | $\begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_{b} \leq 2.7 \ V \end{array}$ | | Note 3 | | Note 3 | bps |
| | | | Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 2.7 k Ω , V_b = 2.3 V | | 1.2 Note 4 | | 1.2 Note 4 | Mbps |
| | | | $\begin{array}{l} 2.7 \ V \leq V_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_{b} \leq 2.0 \ V \end{array}$ | | Note 5, 6 | | Note 5, 6 | bps |
| | | | Theoretical value of the maximum transfer rate C_b = 50 pF, R_b = 5.5 k Ω , V_b = 1.6 V | | 0.43 Note 7 | | 0.43 Note 7 | Mbps |

-40 to +85°C 27V < Von < 55V Vee - 0 //

Note 1. The smaller maximum transfer rate derived by using fMcK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V \leq VDD \leq 5.5 V and 2.7 V \leq Vb \leq 4.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3}$$

$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3} - \{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\}$$
Baud rate error (theoretical value) =
$$\frac{1}{(1 - \frac{2.2}{V_b})} \times 100 \ [\%]$$

Baud rate error (theoretical value) =

(
$$\frac{1}{\text{Transfer rate}}$$
) × Number of transferred bits

* This value is the theoretical value of the relative difference between the transmission and reception sides

Note 2. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.

The smaller maximum transfer rate derived by using fMcK/6 or the following expression is the valid maximum transfer Note 3. rate.

Expression for calculating the transfer rate when 2.7 V \leq VDD < 4.0 V and 2.3 V \leq Vb \leq 2.7 V

Maximum transfer rate =

$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

1

etical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}}$$

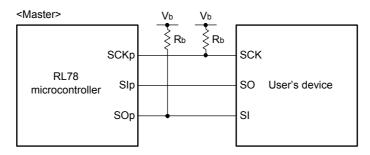
Baud rate error (theore

Note 4. This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 3 above to calculate the maximum transfer rate under conditions of the customer.

Note 5. Use it with $V_{DD} \ge V_b$.

RENESAS

CSI mode connection diagram (during communication at different potential)



Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

Note 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remark 1.** Rb[Ω]: Communication line (SCKp, SOp) pull-up resistance, Cb[F]: Communication line (SCKp, SOp) load capacitance, Vb[V]: Communication line voltage
- Remark 2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 3, 5)
- Remark 3. VIH and VIL below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in CSI mode.

4.0 V \leq VDD \leq 5.5 V, 2.7 V \leq Vb \leq 4.0 V: VIH = 2.2 V, VIL = 0.8 V

- $2.7~V \leq V\text{DD}$ < 4.0 V, 2.3 V $\leq V\text{b} \leq 2.7$ V: VIH = 2.0 V, VIL = 0.5 V
- Remark 4. This value is valid only when CSI00's peripheral I/O redirect function is not used.



(8) Communication at different potential (2.5 V, 3 V) (fMCK/4) (CSI mode) (master mode, SCKp... internal clock output) (TA = -40 to +85°C, 2.7 V \leq VDD \leq 5.5 V, Vss = 0 V)(1/2)

| Parameter | Symbol | Conditions | | HS (high-spee mode | HS (high-speed main) mode | | LS (low-speed main) mode | |
|-----------------------|--------|---|---|-----------------------|---------------------------|---------------|-----------------------------|----|
| | | | | MIN. | MAX. | MIN. | MAX. | |
| SCKp cycle time | tксү1 | tkcy1≥4/fc∟k | | 300 | | 1150 | | ns |
| | | | $\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$ | 500 | | 1150 | | ns |
| | | | $\label{eq:VD} \begin{array}{l} 2.7 \ V \leq V_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V, \\ C_b = 30 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$ | 1150 | | 1150 | | ns |
| SCKp high-level width | tкнı | $\begin{array}{l} 4.0 \ V \leq V_{DD} \leq 5.5 \ \text{V}, \ 2.7 \ V \leq V_b \leq 4.0 \ \text{V}, \\ C_b = 30 \ \text{pF}, \ R_b = 1.4 \ \text{k}\Omega \end{array}$ | | tĸcy1/2 - 75 | | tксү1/2 - 75 | | ns |
| | | $\begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, 2.3 \; V \leq V_{b} \leq 2.7 \; V, \\ \mathbf{C}_{b} = 30 \; pF, \; R_{b} = 2.7 \; k\Omega \end{array}$ | | tксү1/2 - 170 | | tксү1/2 - 170 | | ns |
| | | $2.7 \text{ V} \le \text{V}_{\text{DD}} < 3.$ Cb = 30 pF, Rb = | 3 V, 1.6 V \leq Vb \leq 2.0 V, \leq 5.5 k\Omega | tксү1/2 - 458 | | tксү1/2 - 458 | | ns |
| SCKp low-level width | tĸ∟1 | $\begin{array}{l} 4.0 \ V \leq V_{DD} \leq 5. \\ C_b \ \ = \ \ 30 \ \ pF, \ R_b \ \ \ = \end{array}$ | 5 V, 2.7 V \leq V _b \leq 4.0 V, : 1.4 kΩ | tkcy1/2 - 12 | | tксү1/2 - 50 | | ns |
| | | $\begin{array}{l} 2.7 \; V \leq V_{DD} < 4.0 \; V, 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 30 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$ | | tĸcy1/2 - 18 | | tkcy1/2 - 50 | | ns |
| | | $2.7 V \le V_{DD} < 3.$ C _b = 30 pF, R _b = | 3 V, 1.6 V \leq Vb \leq 2.0 V, = 5.5 k\Omega | tkcy1/2 - 50 | | tĸcy1/2 - 50 | | ns |

Caution 1. Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

Caution 2. Use it with $VDD \ge Vb$.

- **Remark 1.** Rb[Ω]: Communication line (SCKp, SOp) pull-up resistance, Cb[F]: Communication line (SCKp, SOp) load capacitance, Vb[V]: Communication line voltage
- Remark 2. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 3, 5)

Remark 3. VIH and VIL below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in CSI mode.

 $\begin{array}{l} 4.0 \ V \leq V_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_{b} \leq 4.0 \ V; \ V_{IH} = 2.2 \ V, \ V_{IL} = 0.8 \ V \\ 2.7 \ V \leq V_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_{b} \leq 2.7 \ V; \ V_{IH} = 2.0 \ V, \ V_{IL} = 0.5 \ V \end{array}$



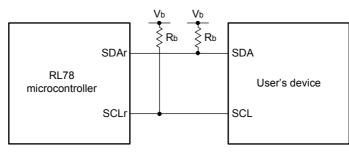
(10) Communication at different potential (2.5 V, 3 V) (simplified I²C mode)

| | | | HS (high- | speed main) | LS (low-s | peed main) | |
|------------------------------|---|--|-----------|-------------|-----------|------------|-----|
| Parameter | $ \begin{array}{ c c c c c c } \hline MIN. & MAX. \\ \hline 1000 Note 1 \\ \hline C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \\ \hline 2.7 \ V \le V_{DD} \le 4.0 \ V, \ 2.3 \ V \le V_b \le 2.7 \ V, \\ \hline C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \\ \hline 4.0 \ V \le V_{DD} \le 5.5 \ V, \ 2.7 \ V \le V_b \le 4.0 \ V, \\ \hline C_b = 100 \ pF, \ R_b = 2.8 \ k\Omega \\ \hline 2.7 \ V \le V_{DD} \le 4.0 \ V, \ 2.3 \ V \le V_b \le 2.7 \ V, \\ \hline C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \\ \hline 2.7 \ V \le V_{DD} \le 4.0 \ V, \ 2.3 \ V \le V_b \le 2.7 \ V, \\ \hline C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \\ \hline 2.7 \ V \le V_{DD} \le 3.3 \ V, \ 1.6 \ V \le V_b \le 2.0 \ V \ Note \ 2, \\ \hline C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \\ \hline \hline 100 \ pF, \ R_b = 5.5 \ k\Omega \\ \hline \hline Time \ when \\ = ``L" \\ \hline \begin{array}{c} time \ when \\ = ``L" \\ \hline time \ when \\ = ``L" \\ \hline \ time \ when \\ = ``L" \\ \hline \ time \ V \ V \ V \ V \ V \ V \ V \ V \ V \ $ | mode | | Unit | | | |
| | | | MIN. | MAX. | MIN. | | |
| SCLr clock frequency | fscl | | | 1000 Note 1 | | 300 Note 1 | kHz |
| | | | | 1000 Note 1 | | 300 Note 1 | kHz |
| | | | | 400 Note 1 | | 300 Note 1 | kHz |
| | | | | 400 Note 1 | | 300 Note 1 | kHz |
| | | | | 300 Note 1 | | 300 Note 1 | kHz |
| Hold time when SCLr = "L" | tLOW | | 475 | | 1550 | | ns |
| | | | 475 | | 1550 | | ns |
| | | | 1150 | | 1550 | | ns |
| | | | 1150 | | 1550 | | ns |
| | | $\begin{array}{l} 2.7 \ \text{V} \leq \text{V}_{\text{DD}} < 3.3 \ \text{V}, \ 1.6 \ \text{V} \leq \text{V}_{\text{b}} < 2.0 \ \text{V} \ \text{Note} \ 2, \\ C_{\text{b}} = 100 \ \text{pF}, \ R_{\text{b}} = 5.5 \ \text{k}\Omega \end{array}$ | 1550 | | 1550 | | ns |
| Hold time when SCLr = "H" | tніgн | $\begin{array}{l} 4.0 \ V \leq V_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_{b} \leq 4.0 \ V, \\ C_{b} = 50 \ pF, \ R_{b} = 2.7 \ k\Omega \end{array}$ | 245 | | 610 | | ns |
| | | $\begin{array}{l} 2.7 \ \text{V} \leq \text{V}_{\text{DD}} < 4.0 \ \text{V}, \ 2.3 \ \text{V} \leq \text{V}_{\text{b}} < 2.7 \ \text{V}, \\ \text{C}_{\text{b}} = 50 \ \text{pF}, \ \text{R}_{\text{b}} = 2.7 \ \text{k}\Omega \end{array}$ | 200 | | 610 | | ns |
| | | $\begin{array}{l} 4.0 \ V \leq V_{DD} \leq 5.5 \ V, \ 2.7 \ V \leq V_{b} \leq 4.0 \ V, \\ C_{b} = 100 \ pF, \ R_{b} = 2.8 \ k\Omega \end{array}$ | 675 | | 610 | | ns |
| | | $\label{eq:VDD} \begin{array}{l} 2.7 \ V \leq V_{DD} < 4.0 \ V, \ 2.3 \ V \leq V_b < 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$ | 600 | | 610 | | ns |
| | | $2.7 \text{ V} \le \text{V}_{\text{DD}}$ < 3.3 V , $1.6 \text{ V} \le \text{V}_{\text{b}}$ < 2.0 V Note 2, Cb = 100 pF, Rb = $5.5 \text{ k}\Omega$ | 610 | | 610 | | ns |

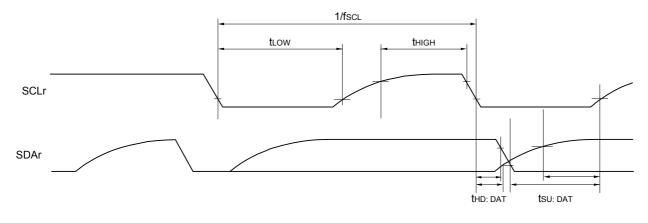
(Notes, Caution and Remarks are listed on the next page.)



Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



Remark 1. Rb[Ω]: Communication line (SDAr, SCLr) pull-up resistance, Cb[F]: Communication line (SDAr, SCLr) load capacitance, Vb[V]: Communication line voltage

Remark 2. r: IIC number (r = 00), g: PIM, POM number (g = 3, 5)

Remark 3. fMCK: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0), n: Channel number (n = 0), mn = 00)

Remark 4. VIH and VIL below are observation points for the AC characteristics of the serial array unit when communicating at different potentials in simplified I²C mode.

4.0 V \leq VDD \leq 5.5 V, 2.7 V \leq Vb \leq 4.0 V: VIH = 2.2 V, VIL = 0.8 V

 $2.7~\text{V} \leq \text{V}\text{DD}$ < $4.0~\text{V},~2.3~\text{V} \leq \text{V}\text{b} \leq 2.7~\text{V}\text{:}$ VIH = 2.0~V,~VIL = 0.5~V



(2) When AVREF (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), AVREF (-) = AVREFM/ANI1 (ADREFM = 1), target ANI pin: ANI16 to ANI19

(TA = -40 to +85°C, 2.7 V \leq VDD \leq 5.5 V, Vss = 0 V, Reference voltage (+) = AVREFP, Reference voltage (-) = AVREFM = 0 V)

| Parameter | Symbol | Co | onditions | MIN. | TYP. | MAX. | Unit |
|--|--------|---|---|--------|------|--------|-------|
| Resolution | Res | | | 8 | | 10 | bit |
| Overall error Note 1 | AINL | 10-bit resolution AVREFP = VDD | $2.7 \text{ V} \leq \text{V}\text{DD} \leq 5.5 \text{ V}$ | | 1.2 | ±5.0 | LSB |
| Conversion time | tCONV | 10-bit resolution AVREFP = VDD | $3.6~V \leq V \text{DD} \leq 5.5~V$ | 2.125 | | 39 | μs |
| | | | $2.7~V \leq V\text{DD} \leq 5.5~V$ | 3.1875 | | 39 | μS |
| Zero-scale error Notes 1, 2 | EZS | 10-bit resolution AVREFP = VDD | $2.7 \text{ V} \leq \text{V}\text{DD} \leq 5.5 \text{ V}$ | | | ±0.35 | % FSR |
| Full-scale error Notes 1, 2 | EFS | 10-bit resolution AVREFP = VDD | $2.7~V \leq V_{DD} \leq 5.5~V$ | | | ±0.35 | % FSR |
| Integral linearity error Note 1 | ILE | 10-bit resolution AVREFP = VDD | $2.7~V \leq V_{DD} \leq 5.5~V$ | | | ±3.5 | LSB |
| Differential linearity error Note 1 | DLE | 10-bit resolution AVREFP = VDD | $2.7 \text{ V} \leq \text{VDD} \leq 5.5 \text{ V}$ | | | ±2.0 | LSB |
| Reference voltage (+) | AVREFP | | | 2.7 | | Vdd | V |
| Analog input voltage | VAIN | | | 0 | | AVREFP | V |
| | Vbgr | Select internal reference of the select of the select internal reference of the select the select of the select o | | 1.38 | 1.45 | 1.5 | V |

Note 1. Excludes quantization error (±1/2 LSB).

Note 2. This value is indicated as a ratio (% FSR) to the full-scale value.



2.7.2 Temperature sensor characteristics

| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|-----------------------------------|---------|--|------|------|------|-------|
| Temperature sensor output voltage | VTMPS25 | Setting ADS register = 80H, TA = +25°C | | 1.05 | | V |
| Reference output voltage | VCONST | Setting ADS register = 81H | 1.38 | 1.45 | 1.5 | V |
| Temperature coefficient | FVTMPS | Temperature sensor that depends on the temperature | | -3.6 | | mV/°C |
| Operation stabilization wait time | tamp | | 5 | | | μS |

(TA = -40 to +85°C, 2.7 V \leq VDD \leq 5.5 V, Vss = 0 V, HS (high-speed main) mode)

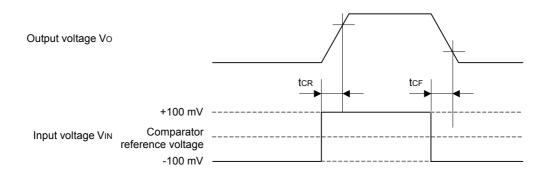
2.7.3 Comparator

(Ta = -40 to +85°C, 2.7 V \leq VDD \leq 5.5 V, Vss = 0 V)

| Parameter | Symbol | Conditions | | MIN. | TYP. | MAX. | Unit |
|---|----------|---|--------------------|------|------|------|------|
| Input offset voltage | VIOCMP | | | | ±5 | ±40 | mV |
| Input voltage range | VICMP | | | 0 | | Vdd | V |
| Internal reference voltage deviation | ΔViref | CmRVM register value: 7FH to 80H (m = 0, 1) | | | | ±2 | LSB |
| | | Other than above | | | | ±1 | LSB |
| Response time | tCR, tCF | Input amplitude = ±100 mV | | | 70 | 150 | ns |
| Operation stabilization time Note 1 | tсмр | CMPnEN = 0→1 VDD = 3.3 to 5.5 V | | | | 1 | μS |
| | | | VDD = 2.7 to 3.3 V | | | 3 | |
| Reference voltage stabilization wait time | tvr | CVRE: 0→1 Note 2 | • | | | 20 | μS |

Note 1. Time required after the operation enable signal of the comparator has been changed (CMPnEN = $0 \rightarrow 1$) until a state satisfying the DC and AC characteristics of the comparator is entered.

Note 2. Enable operation of internal reference voltage generation (CVREm bit = 1; m = 0, 1) and wait for the operation stabilization wait time before enabling the comparator output (CnOE bit = 1; n = 0, 1).





2.7.6 LVD circuit characteristics

| Para | meter | Symbol | Symbol Conditions MIN. | | TYP. | MAX. | Unit |
|-----------------|---------------|--------|------------------------|------|------|------|------|
| Detection | Supply | VLVD0 | Power supply rise time | 3.98 | 4.06 | 4.14 | V |
| voltage | voltage level | | Power supply fall time | 3.90 | 3.98 | 4.06 | V |
| | | VLVD1 | Power supply rise time | 3.68 | 3.75 | 3.82 | V |
| | | | Power supply fall time | 3.60 | 3.67 | 3.74 | V |
| | VLVD2 | | Power supply rise time | 3.07 | 3.13 | 3.19 | V |
| | | | Power supply fall time | 3.00 | 3.06 | 3.12 | V |
| | | Vlvd3 | Power supply rise time | 2.96 | 3.02 | 3.08 | V |
| | | | Power supply fall time | 2.90 | 2.96 | 3.02 | V |
| | | VLVD4 | Power supply rise time | 2.86 | 2.92 | 2.97 | V |
| | | | Power supply fall time | 2.80 | 2.86 | 2.91 | V |
| | | VLVD5 | Power supply rise time | 2.76 | 2.81 | 2.87 | V |
| | | | Power supply fall time | 2.70 | 2.75 | 2.81 | V |
| Minimum pulse | e width | t∟w | | 300 | | | μS |
| Detection delay | y time | tld | | | | 300 | μS |

(TA = -40 to +85°C, VPDR \leq VDD \leq 5.5 V, VSS = 0 V)

Remark VLVD (n - 1) > VLVDn: n = 1 to 5



LVD Detection Voltage of Interrupt & Reset Mode

| Parameter | Symbol | Conditions | | | | TYP. | MAX. | Unit |
|---------------------|--------|---------------------|---|------------------------------|------|------|------|------|
| Interrupt and reset | VLVD5 | VPOC2, | VPOC2, VPOC1, VPOC0 = 0, 1, 1, falling reset voltage: 2.7 V | | | | 2.81 | V |
| mode | VLVD4 | | LVIS1, LVIS0 = 1, 0 | Rising release reset voltage | 2.86 | 2.92 | 2.97 | V |
| VLVD3 VLVD0 | | | (+0.1 V) | Falling interrupt voltage | 2.80 | 2.86 | 2.91 | V |
| | | LVIS1, LVIS0 = 0, 1 | Rising release reset voltage | 2.96 | 3.02 | 3.08 | V | |
| | | (+ | (+0.2 V) | Falling interrupt voltage | 2.90 | 2.96 | 3.02 | V |
| | VLVD0 | LVIS1, LVIS0 = 0, 0 | Rising release reset voltage | 3.98 | 4.06 | 4.14 | V | |
| | | (+1.2 V) | Falling interrupt voltage | 3.90 | 3.98 | 4.06 | V | |

(TA = -40 to +85°C, VPDR \leq VDD \leq 5.5 V, VSS = 0 V)

2.7.7 Power supply voltage rising slope characteristics

(TA = -40 to +85°C, Vss = 0 V)

| Parameter | Symbol | Conditions | MIN. | TYP. | MAX. | Unit |
|-----------------------------------|--------|------------|------|------|------|------|
| Power supply voltage rising slope | SVDD | | | | 54 | V/ms |

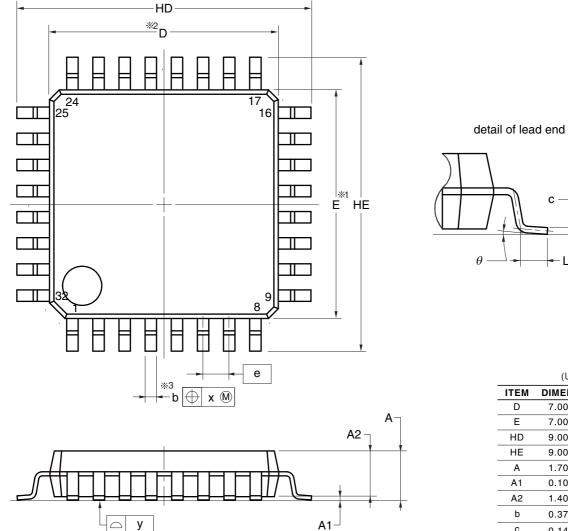
Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until VDD reaches the operating voltage range shown in 2.5 AC Characteristics.



32-pin Products 3.2

R5F11EB8AFP, R5F11EBAAFP

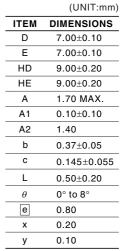
| JEITA Package Code | RENESAS Code | Previous Code | MASS (TYP.) [g] |
|--------------------|--------------|----------------|-----------------|
| P-LQFP32-7x7-0.80 | PLQP0032GB-A | P32GA-80-GBT-1 | 0.2 |



NOTE

1.Dimensions " \gg 1" and " \gg 2" do not include mold flash.

2.Dimension "%3" does not include trim offset.



- 1



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